

AO3416

20V N-Channel MOSFET

General Description

The AO3416 uses advanced trench technology to provide excellent $R_{\text{DS(ON)}}$, low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch or in PWM applications. It is ESD protected.

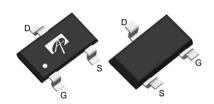
Product Summary

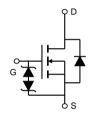
 $\begin{array}{lll} V_{DS} & 20V \\ I_{D} \; (at \; V_{GS} \! = \! 4.5V) & 6.5A \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 4.5V) & < 22m\Omega \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 2.5V) & < 26m\Omega \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 1.8V) & < 34m\Omega \end{array}$

ESD protected



SOT23 Top View Bottom View





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Absolute Maximum Ratings 1,4-23 C unless otherwise noted							
Parameter		Symbol	Maximum	Units			
Drain-Source Voltage		V _{DS}	20	V			
Gate-Source Voltage		V _{GS}	±8	V			
Continuous Drain	T _A =25°C		6.5				
Current	T _A =70°C	'D	5.2	A			
Pulsed Drain Current ^C		I _{DM}	30				
	T _A =25°C	P _D	1.4	W			
Power Dissipation ^B	T _A =70°C	r _D	0.9	VV			
Junction and Storage Temperature Range T		T _J , T _{STG}	-55 to 150	°C			

Thermal Characteristics							
Parameter	Symbol	Тур	Max	Units			
Maximum Junction-to-Ambient ^A	t ≤ 10s	D	70	90	°C/W		
Maximum Junction-to-Ambient AD	Steady-State $R_{\theta JA}$		100	125	°C/W		
Maximum Junction-to-Lead	Steady-State	$R_{\theta JL}$	63	80	°C/W		



Electrical Characteristics (T_{.1}=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V		20			V
I _{DSS}	Zero Gate Voltage Drain Current	V_{DS} =20V, V_{GS} =0V				1	μА
D00		T _J =55°C				5	μπ
I_{GSS}	Gate-Body leakage current	V_{DS} =0V, V_{GS} = ±8V				±10	μΑ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_{D}=250\mu A$		0.4	0.7	1.1	V
$I_{D(ON)}$	On state drain current	V_{GS} =4.5V, V_{DS} =5V		30			Α
		V_{GS} =4.5V, I_{D} =6.5A			16	22	mΩ
R _{DS(ON)}	Static Drain-Source On-Resistance		T _J =125°C		22	30	1115.2
TYDS(ON)	Static Diam-Source On-Nesistance	V_{GS} =2.5V, I_{D} =5.5A			18	26	mΩ
		V_{GS} =1.8V, I_D =5A			21	34	mΩ
g _{FS}	Forward Transconductance	V_{DS} =5V, I_D =6.5A			50		S
V_{SD}	Diode Forward Voltage	I _S =1A,V _{GS} =0V			0.62	1	V
I _S	Maximum Body-Diode Continuous Current					2	Α
DYNAMIC	PARAMETERS						
C _{iss}	Input Capacitance				1295	1650	pF
C _{oss}	Output Capacitance	V _{GS} =0V, V _{DS} =10V, f=1MHz			160		pF
C_{rss}	Reverse Transfer Capacitance				87		pF
R_g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz			1.8		KΩ
SWITCHI	NG PARAMETERS						
Q_g	Total Gate Charge	V _{GS} =4.5V, V _{DS} =10V, I _D =6.5A			10		nC
Q_{gs}	Gate Source Charge				4.2		nC
Q_{gd}	Gate Drain Charge				2.6		nC
t _{D(on)}	Turn-On DelayTime				280		ns
t _r	Turn-On Rise Time	V_{GS} =4.5V, V_{DS} =10V, R_L =1.54 Ω , R_{GEN} =3 Ω			328		ns
t _{D(off)}	Turn-Off DelayTime				3.76		us
t _f	Turn-Off Fall Time	1	•		2.24		us
t _{rr}	Body Diode Reverse Recovery Time	I _F =6.5A, dI/dt=100A/μs			31	41	ns
Q_{rr}	Body Diode Reverse Recovery Charge	I _F =6.5A, dI/dt=100A/μs			6.8		nC

A. The value of R_{BJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C. The value in any given application depends on the user's specific board design.

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B. The power dissipation P_D is based on $T_{J(MAX)}$ =150° C, using \leq 10s junction-to-ambient thermal resistance.

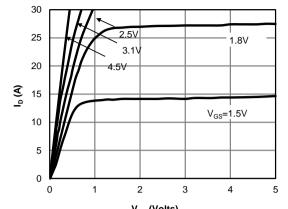
C. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150° C. Ratings are based on low frequency and duty cycles to keep initialT₁=25° C.

D. The R_{NJA} is the sum of the thermal impedence from junction to lead R_{NJL} and lead to ambient. E. The static characteristics in Figures 1 to 6 are obtained using <300 μ s pulses, duty cycle 0.5% max.

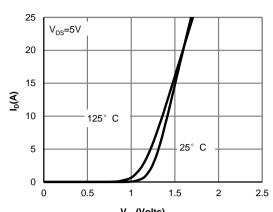
F. These curves are based on the junction-to-ambient thermal impedence which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of T_{J(MAX)}=150° C. The SOA curve provides a single pulse rating.



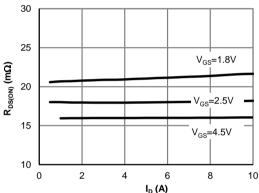
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



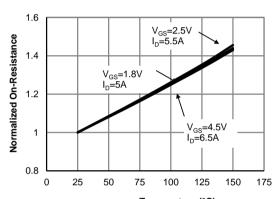
V_{DS} (Volts) Fig 1: On-Region Characteristics (Note E)



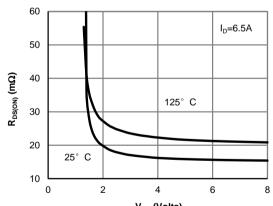
V_{GS}(Volts)
Figure 2: Transfer Characteristics (Note E)



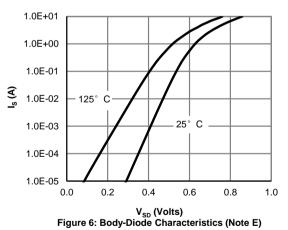
 $\rm I_D\left(A\right)$ Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)



Temperature (°C)
Figure 4: On-Resistance vs. Junction Temperature
(Note E)



V_{GS} (Volts)
Figure 5: On-Resistance vs. Gate-Source Voltage
(Note E)





TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

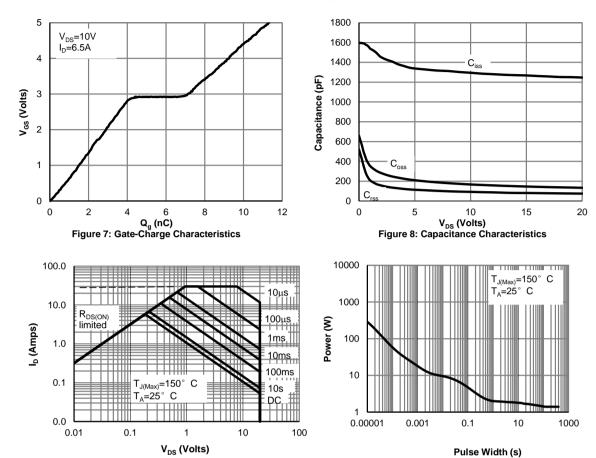
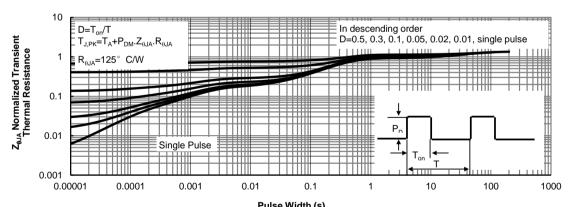


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

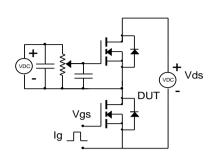
Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

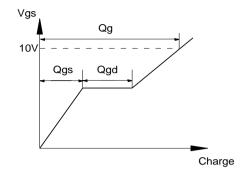


Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

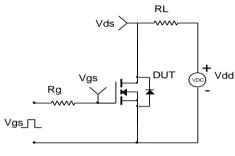


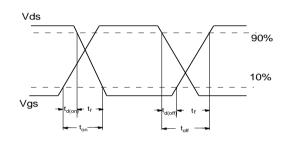
Gate Charge Test Circuit & Waveform





Resistive Switching Test Circuit & Waveforms





Diode Recovery Test Circuit & Waveforms

